

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/534,048	TERADA, YUICHI	
Examiner		Art Unit		
Mohammad M. Ali		3744	Page 1 of 1	

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*	B	US-2002/0144513	10-2002	Gunji et al.	62/263
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